

Search Notes

Application/Control No.

10/664,777

Examiner

M. Lee

Applicant(s)/Patent under Reexamination

IWASE, HIROYUKI

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	722, 589	4/27/2006	ML
	570		
	575		
	578		
	584		
	594		
	595		
	705		
	706		
386	52		
715	723		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	4/27/2006	ML

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner